## ABSTRACT

Flickering due to random noise is appropriately reduced from analysis images used for failure analysis of semiconductor devices. A learning method is a method for generating an inference model used to reduce flickering due to random noise from analysis images used for failure analysis of semiconductor devices, and includes: a learning acquisition step (S01) of acquiring a analysis image for learning that includes a target signal related to a semiconductor device and includes random noise, and a noise image for learning that does not include the target signal and includes random noise; a noise addition step (S02, S03) of reducing contrast of the analysis image for learning, adding the random noise of the noise image for learning to the analysis image for learning with reduced contrast, and generating a noise-added image for learning; and a training step (S04) of performing machine learning training of the inference model using the noise-added image for learning.

Fig. 6